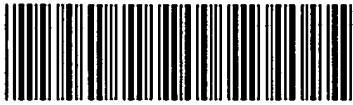


Search Notes

Application/Control No.

10/779,712

Examiner

Wen-Ying P. Chen

Applicant(s)/Patent under
Reexamination

FUJITA ET AL.

Art Unit

2871

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Citations search of tagged references	12/13/2005	WPC
349/155-157 combined with key word search of all databases in EAST	12/14/2005	WPC
Reviewed previously cited references	12/14/2005	WPC